

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

Attorney Docket Number	1011-54375-01
Application Number	09/620,021
Filing Date	July 20, 2000
First Named Inventor	Rajski
Art Unit	<del>2113</del> 2117
Examiner Name	Phung M. Chung

**U.S. PATENT DOCUMENTS**

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Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
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		Examiner Name	Phung M. Chung

  

Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS
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